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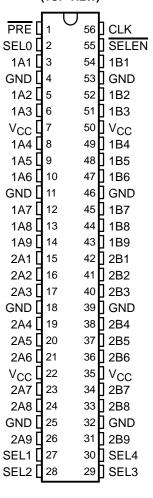
 Widebus+™ Family
- EPIC[™] (Enhanced-Performance Implanted CMOS) Submicron Process
- B-Port Outputs Have Equivalent 26-Ω
 Series Resistors, So No External Resistors
 Are Required
- UBE™ (Universal Bus Exchanger) Allows Synchronous Data Exchange
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 9-bit, 4-port universal bus exchanger is designed for 2.3-V to 3.6-V V_{CC} operation.

The SN74ALVCHR162409 allows synchronous data exchange between four different buses. Data flow is controlled by the select (SEL0–SEL4) inputs. A data-flow state is stored on the rising edge of the clock (CLK) input if the select-enable (SELEN) input is low. Once a data-flow state has been established, data is stored in the flip-flop on the rising edge of CLK if SELEN is high.

DGG OR DL PACKAGE (TOP VIEW)



The data-flow control logic is designed to allow glitch-free data transmission.

The B outputs, which are designed to sink up to 12 mA, include equivalent 26- Ω resistors to reduce overshoot and undershoot.

When preset (PRE) transitions high, the outputs are disabled immediately without waiting for a clock pulse. To leave the high-impedance state, both PRE and SELEN must be low and a clock pulse must be applied.

To ensure the high-impedance state during power up or power down, \overline{PRE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCHR162409 is characterized for operation from –40°C to 85°C.



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Function Tables

FUNCTION

	INPUTS	OUTPUT
CLK	SEND PORT	RECEIVE PORT
Х	Х	_{B0} †
Х	L	L
Х	Н	Н
\uparrow	L	L
1	Н	Н
Н	X	в ₀ †
L	X	_{B0} †

[†]Output level before the indicated steady-state input conditions established



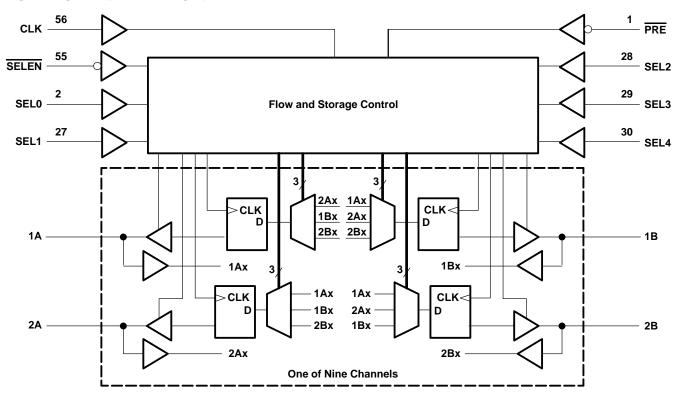
Function Tables (Continued)

DATA-FLOW CONTROL

		INPU	ITS				DATA FLOW	
PRE	SELEN	CLK	SEL0	SEL1	SEL2	SEL3	SEL4	DATA FLOW
Н	Х	Χ	Х	Х	Х	Χ	Χ	All outputs disabled
L	Н	1	Х	Χ	Χ	Χ	Χ	No change
L	L	1	0	0	0	0	0	None, all I/Os off
L	L	1	0	0	0	0	1	Not used
L	L	\uparrow	0	0	0	1	0	Not used
L	L	1	0	0	0	1	1	Not used
L	L	1	0	0	1	0	0	Not used
L	L	1	0	0	1	0	1	Not used
L	L	1	0	0	1	1	0	Not used
L	L	1	0	0	1	1	1	Not used
L	L	1	0	1	0	0	0	2A to 1A and 1B to 2B
L	L	1	0	1	0	0	1	2A to 1A
L	L	1	0	1	0	1	0	2B to 1B
L	L	1	0	1	0	1	1	2A to 1A and 2B to 1B
L	L	1	0	1	1	0	0	1A to 2A and 1B to 2B
L	L	1	0	1	1	0	1	1A to 2A
L	L	\uparrow	0	1	1	1	0	1B to 2B
L	L	1	0	1	1	1	1	1A to 2A and 2B to 1B
L	L	1	1	0	0	0	0	1A to 1B and 2B to 2A
L	L	1	1	0	0	0	1	1A to 1B
L	L	1	1	0	0	1	0	2A to 2B
L	L	1	1	0	0	1	1	1A to 1B and 2A to 2B
L	L	1	1	0	1	0	0	1B to 1A and 2A to 2B
L	L	1	1	0	1	0	1	1B to 1A
L	L	\uparrow	1	0	1	1	0	2B to 2A
L	L	1	1	0	1	1	1	1B to 1A and 2B to 2A
L	L	\uparrow	1	1	0	0	0	2B to 1A and 2A to 1B
L	L	1	1	1	0	0	1	1B to 2A
L	L	1	1	1	0	1	0	2B to 1A
L	L	1	1	1	0	1	1	2B to 1A and 1B to 2A
L	L	1	1	1	1	0	0	1A to 2B and 1B to 2A
L	L	1	1	1	1	0	1	1A to 2B
L	L	1	1	1	1	1	0	2A to 1B
L	L	1	1	1	1	1	1	1A to 2B and 2A to 1B



logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

	0.51// 4.01/
Supply voltage range, V _{CC}	
Input voltage range, V _I : Except I/O ports (see Note 1)	
I/O ports (see Notes 1 and 2)	0.5 V to V _{CC} + 0.5 V
Output voltage range, VO (see Notes 1 and 2)	0.5 V to V _{CC} + 0.5 V
Input clamp current, $I_{ K }(V_{ } < 0)$	
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±50 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±50 mA
Continuous current through each V _{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T _{stq}	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

- 2. This value is limited to 4.6 V maximum.
- 3. The package thermal impedance is calculated in accordance with JESD 51.



SN74ALVCHR162409 9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER WITH 3-STATE OUTPUTS SCES056B - SEPTEMBER 1995 - REVISED JULY 1997

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
Vcc	Supply voltage		2.3	3.6	V
	High level input veltage	$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2		V
VIΗ	High-level input voltage VCC = 2.3		1.7		V
\/	Low-level input voltage	$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$		0.8	V
۷IL	Low-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		0.7	V
٧ _I	Input voltage		0	VCC	V
٧o	Output voltage		0	VCC	V
		$V_{CC} = 2.3 \text{ V}$		-6	
ІОН	High-level output current	$V_{CC} = 2.7 \text{ V}$		-8	mA
V _O IOH IOL Δt/Δv		V _{CC} = 3 V		-12	
		V _{CC} = 2.3 V			
lOL	Low-level output current	$V_{CC} = 2.7 \text{ V}$		8	mA
			12		
Δt/Δν	Input transition rise or fall rate		0	10	ns/V
TA	Operating free-air temperature		-40	85	°C

NOTE 4: Unused control inputs must be held high or low to prevent them from floating.

SN74ALVCHR162409 9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PA	RAMETER	TEST C	ONDITIONS	VCC	MIN	TYP†	MAX	UNIT	
		I _{OH} = -100 μA		2.3 V to 3.6 V	V _{CC} -0.2				
Vari	I _{OH} = -4 mA,	V _{IH} = 1.7 V	2.3 V	1.9					
	I _{OH} = -6 mA	V _{IH} = 1.7 V	2.3 V	1.7			v		
VOH		IOH = -0 IIIA	V _{IH} = 2 V	3 V	2.4			V	
VOH VOL II	$I_{OH} = -8 \text{ mA},$	V _{IH} = 2 V	2.7 V	2					
	$I_{OH} = -12 \text{ mA},$	V _{IH} = 2 V	3 V	2					
		$I_{OL} = 100 \mu A$,		2.3 V to 3.6 V			0.2		
		$I_{OL} = 4 \text{ mA},$	V _{IL} = 0.7 V	2.3 V			0.4		
\ \/a.		lo 6 m/	V _{IL} = 0.7 V	2.3 V			0.55	V	
VOL		IOL = 6 mA	V _{IL} = 0.8 V	3 V			0.55		
	I _{OL} = 8 mA,	V _{IL} = 0.8 V	2.7 V			0.6			
		I _{OL} = 12 mA,	V _{IL} = 0.8 V	3 V			0.8		
IĮ		$V_I = V_{CC}$ or GND		3.6 V			±5	μΑ	
		V _I = 0.7 V		2.3 V	45				
		V _I = 1.7 V		2.3 V	-45				
I _{I(hold)}		V _I = 0.8 V		3 V	75			μΑ	
		V _I = 2 V		3 V	-75				
		$V_{I} = 0 \text{ to } 3.6 \text{ V}^{\ddagger}$		3.6 V			±500		
loz§		$V_O = V_{CC}$ or GND		3.6 V			±10	μΑ	
Icc		$V_I = V_{CC}$ or GND,	IO = 0	3.6 V			40	μΑ	
Δlcc		One input at V _{CC} – 0.6 V,	Other inputs at V _{CC} or GND	3 V to 3.6 V			750	μΑ	
Ci	Control inputs	V _I = V _{CC} or GND		3.3 V		4		pF	
C _{io}	A or B ports	$V_O = V_{CC}$ or GND		3.3 V		8		pF	

[†] All typical values are measured at $V_{CC} = 3.3 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

			V _{CC} =		V _{CC} =	2.7 V	V _{CC} =		UNIT	
			MIN	MAX	MIN	MAX	MIN	MAX		
fclock	Clock frequency		0	120	0	120	0	120	MHz	
t _W	Pulse duration, CLK high or low		4.2		4.2		3		ns	
	Setup time	A or B before CLK↑	1.9		1.9		1.4		ns	
		SEL before CLK↑	5.1		4.2		3.5			
t _{su}		SELEN before CLK↑	2.5		2.5		1.8			
		PRE before CLK↑	1		1		0.7			
		A or B after CLK↑	0.8		0.8		1			
th	Hold time	SEL after CLK↑	0		0		0		ns	
		SELEN after CLK↑	0.5		0.5		0.8			



[‡] This is the bus-hold maximum dynamic current required to switch the input from one state to another.

[§] For I/O ports, the parameter IOZ includes the input leakage current.

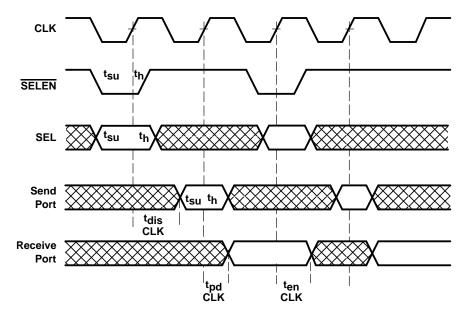
switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figures 1 and 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
	(1141-01)	(0011 01)	MIN	MAX	MIN	MAX	MIN	MAX	
fmax			120		120		120		MHz
t _{pd}	CLK	A or B	2	7.5		7	1.5	6.2	ns
t _{en}	CLK	A or B	2.5	8.3		7.6	2	6.8	ns
^t dis	CLK	A or B	3	7.8		6.4	2	6.1	20
	PRE	AUID	3.5	8.4		7	2.5	6.4	ns

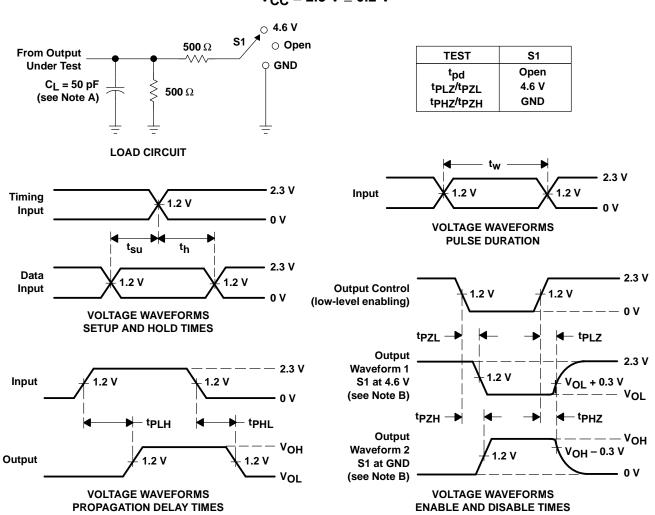
operating characteristics, T_A = 25°C

	PARAMETER	TEST CON		V _{CC} = 2.5 V ± 0.2 V	V _{CC} = 3.3 V ± 0.3 V	UNIT	
					TYP	TYP	
	Power dissipation capacitance	Outputs enabled	C 50 pE	f = 10 MHz	60	60	pF
C _{pd}	rowei dissipation capacitance	Outputs disabled	C _L = 50 pF,	1 = 10 NIM2	60	60	þΓ

timing diagram



PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$



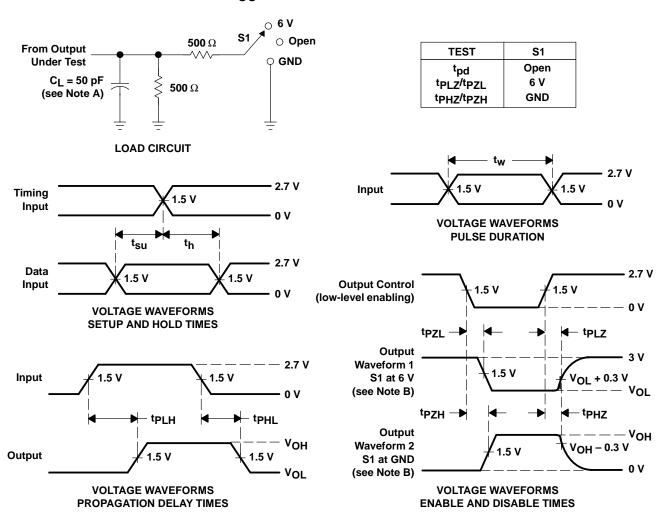
NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \,\Omega$, $t_f \leq 2.5 \,$ ns, $t_f \leq 2.5 \,$ ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpl 7 and tpH7 are the same as tdis.
- F. tpZL and tpZH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



PARAMETER MEASUREMENT INFORMATION V_{CC} = 2.7 V AND 3.3 V \pm 0.3 V



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f \leq 2.5$ ns, $t_f \leq 2.5$ ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpl 7 and tpH7 are the same as tdis.
- F. tpZL and tpZH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 2. Load Circuit and Voltage Waveforms

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